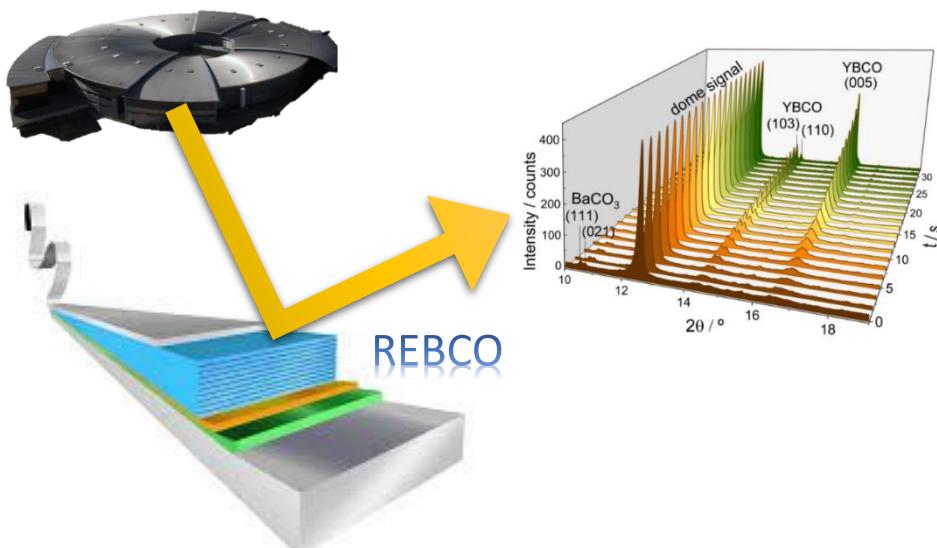


In-situ X-Ray Diffraction revealing the reaction mechanism of ultrafast Transient Liquid Assisted Growth of superconducting thin films

Elzbieta Pach¹

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Institut de Ciència de Materials de Barcelona¹, ICMAB-CSIC, Spain
GRMT, University of Girona², Spain
ALBA Synchrotron³, Cerdanyola del Vallès, Spain
SOLEIL Synchrotron⁴, Saint Aubin, France



Who are we and what do we do?

An interdisciplinary group of physicists, chemists, materials scientists and engineers committed to enable High Temperature Superconducting materials in our society.

Investigating fundamental understanding on Materials & Science of Superconductors to process scalability and integration in devices.



Prof. Rosa Palacin, ICMAB
BATTERIES + SUPERCONDUCTORS



NET-ZERO INDUSTRY ACT *by European Commission*

“Net-zero” CO₂ emissions by 2050

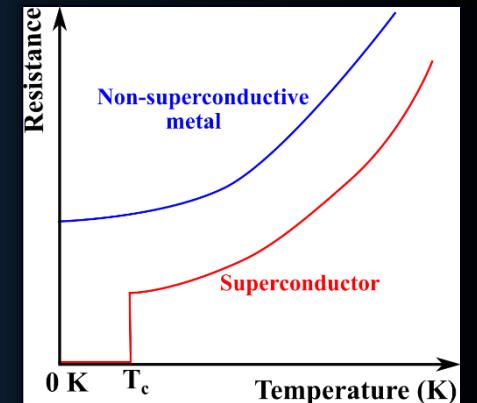
Functional materials for energy applications



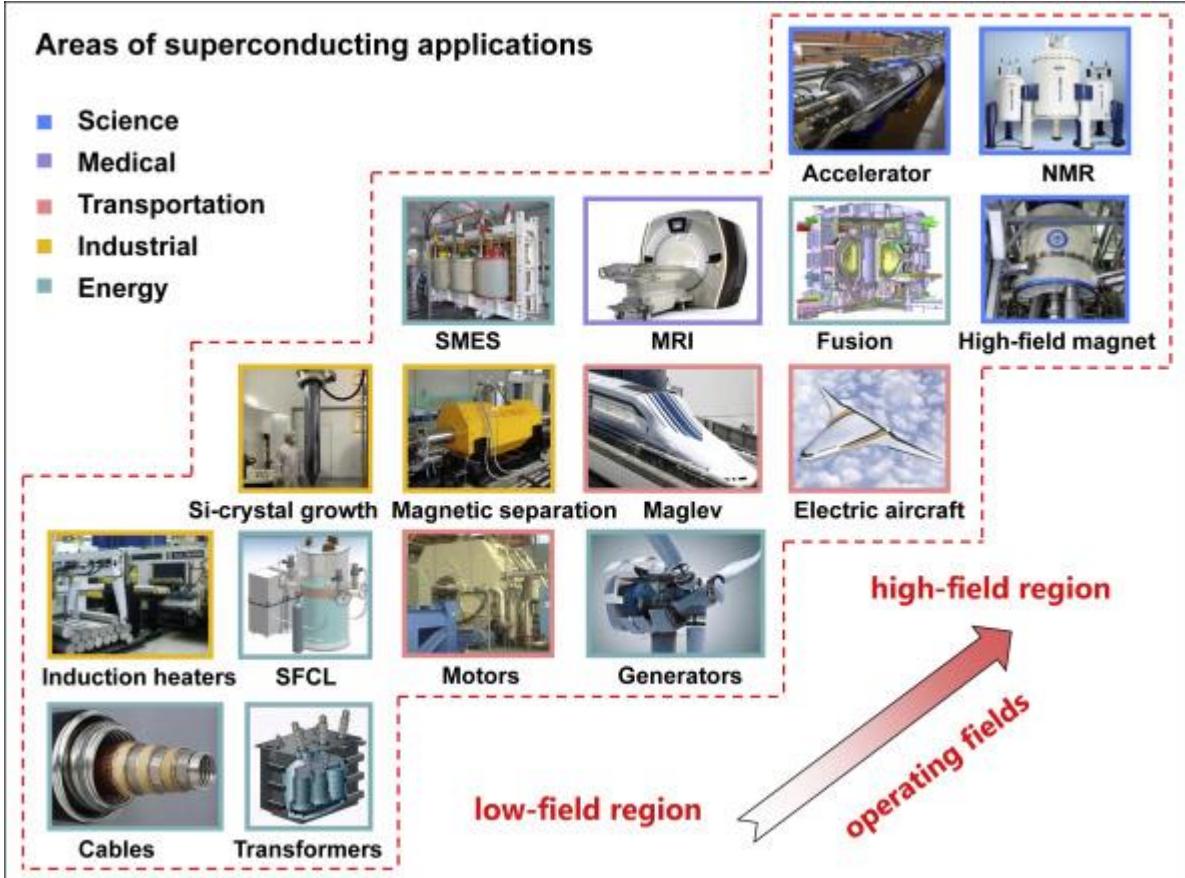
Why do we do what we do?

Superconducting Materials

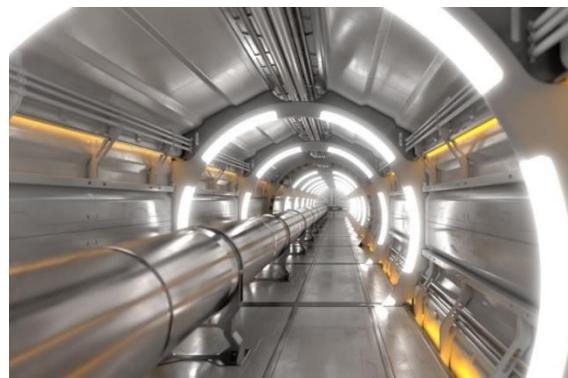
- Lossless electrical transport
- Efficient energy transportation
- Enhance resilience of power grids
- New possibilities at high magnetic fields



The power of High Temperature Superconductors



iScience 2021, Volume 24, Issue 6, 102541, <https://doi.org/10.1016/j.isci.2021.102541>

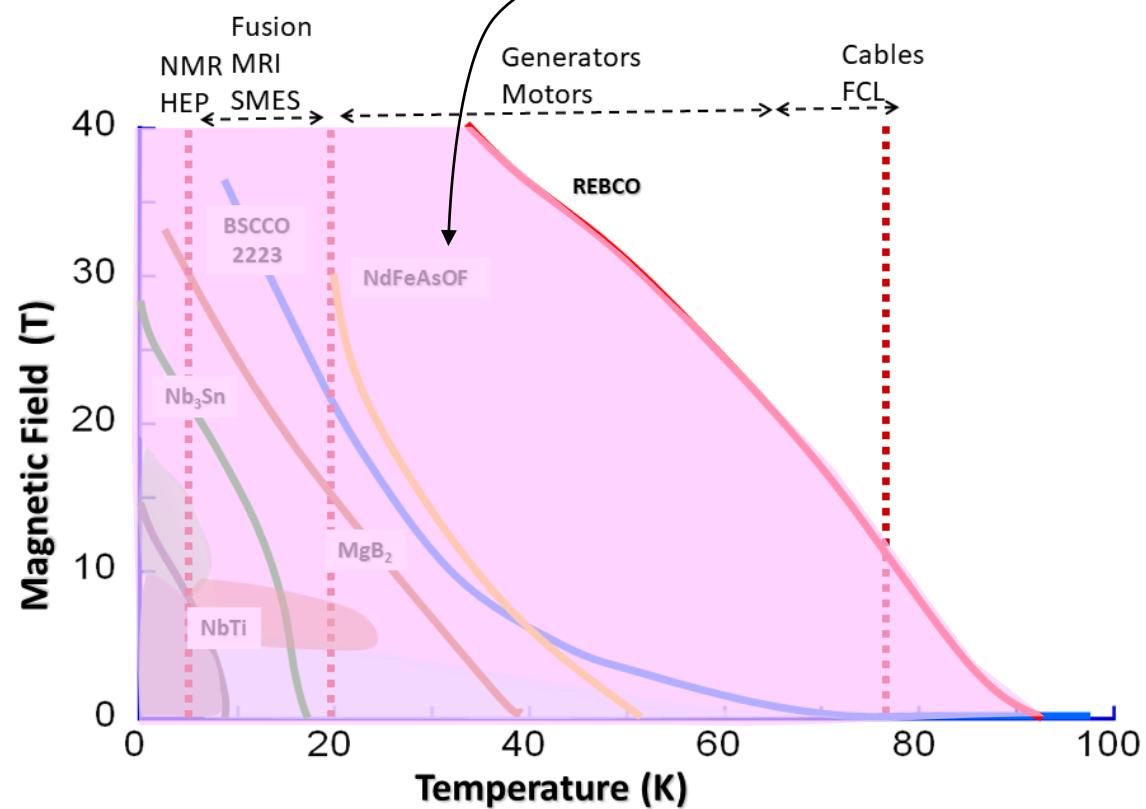
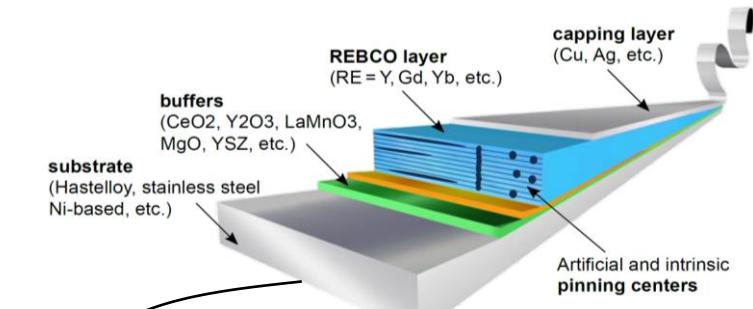
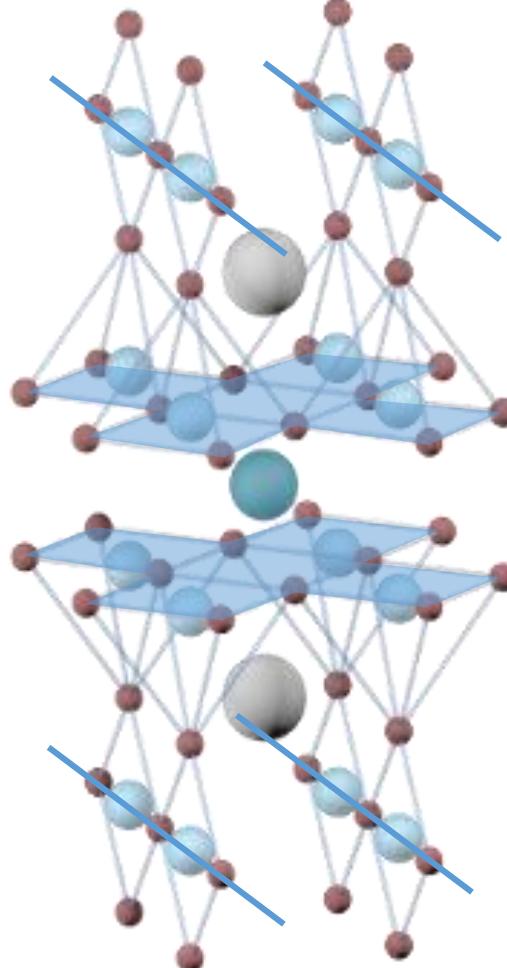


Next generation High Energy Colliders



REBCO = The highest field and highest temperature superconductor

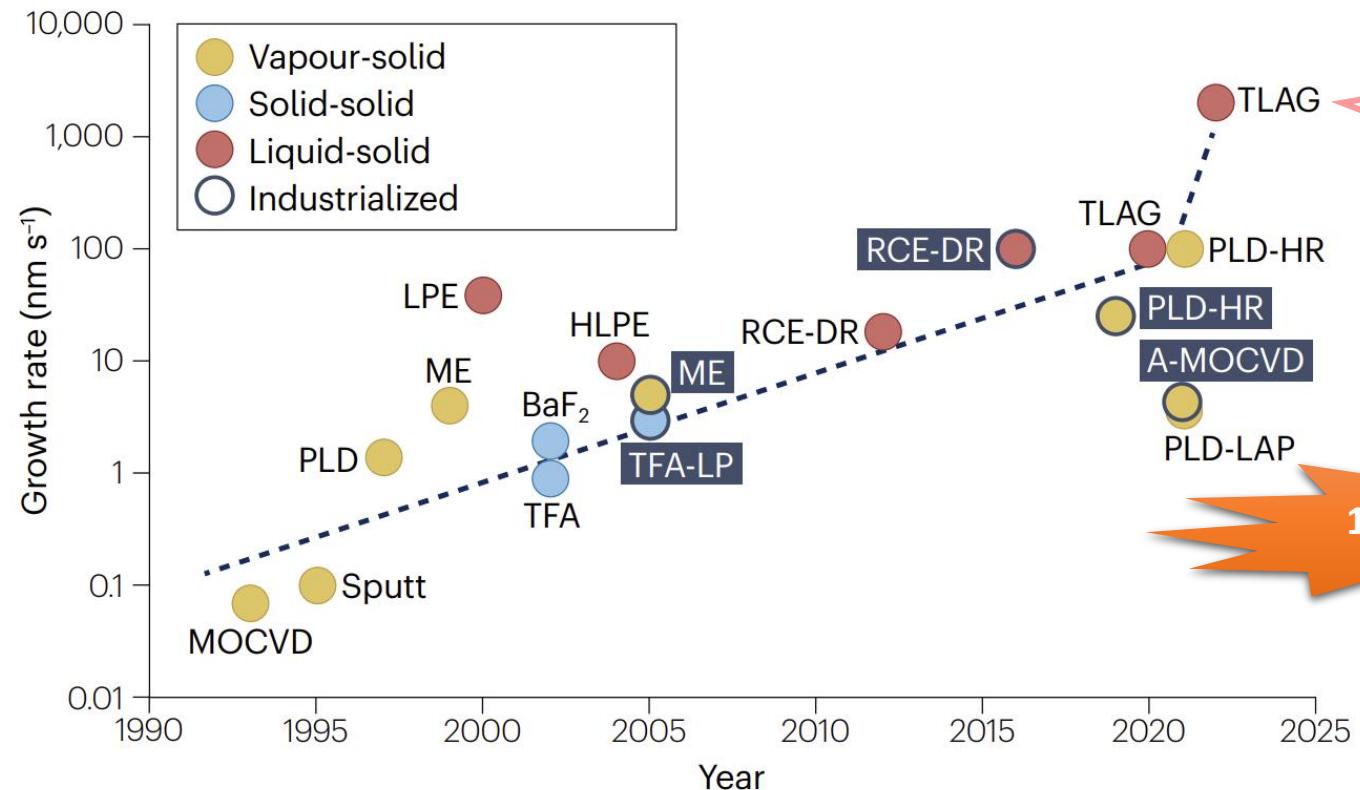
$\text{REBa}_2\text{Cu}_3\text{O}_{7-x}$, RE= Y, Rare Earth



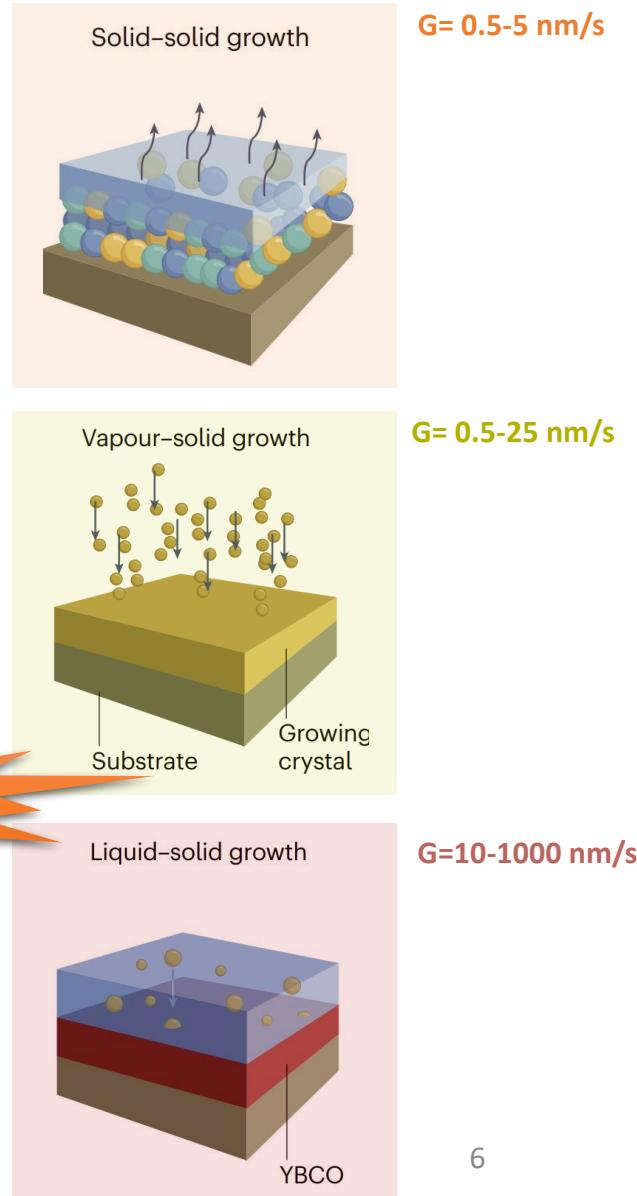
Reaching high Growth Rates: A path towards cost reduction

$$\frac{Cost}{Performance} = \frac{\text{total cost per year}}{G \times L \times W \times (I_{c-w}/d)} = \frac{\text{€}}{kA \times m}$$

G= growth rate
W= tape width
L= tape length
d=tape thickness

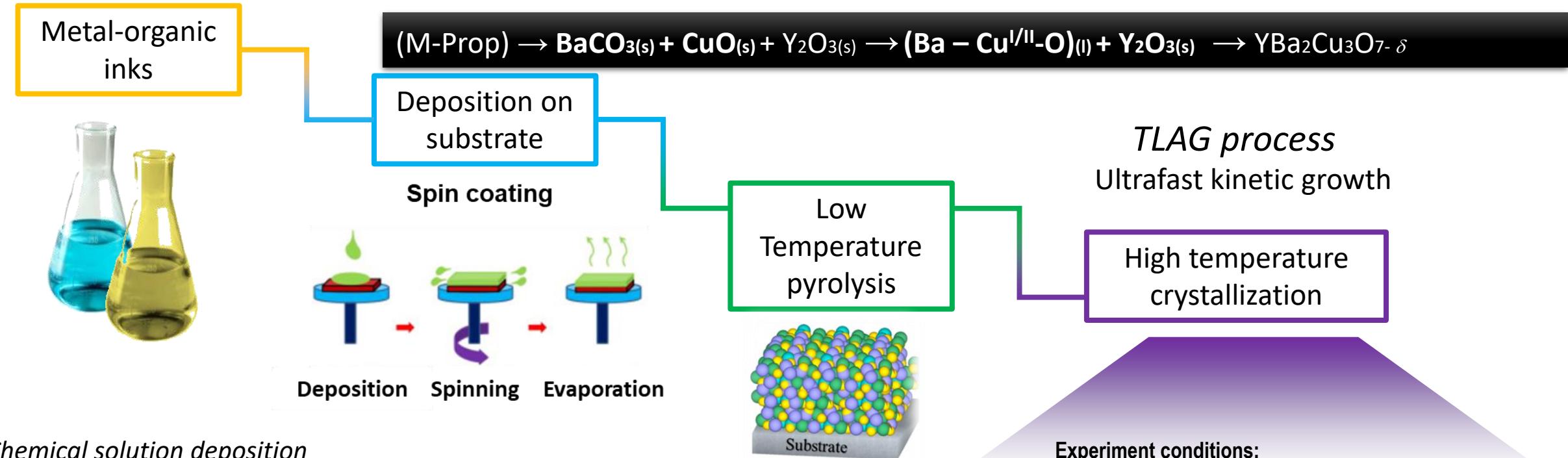


10-20 x G_{industry}



Transient Liquid Assisted Growth of REBCO films

High-throughput, scalable and low cost production of Coated Conductors



Chemical solution deposition

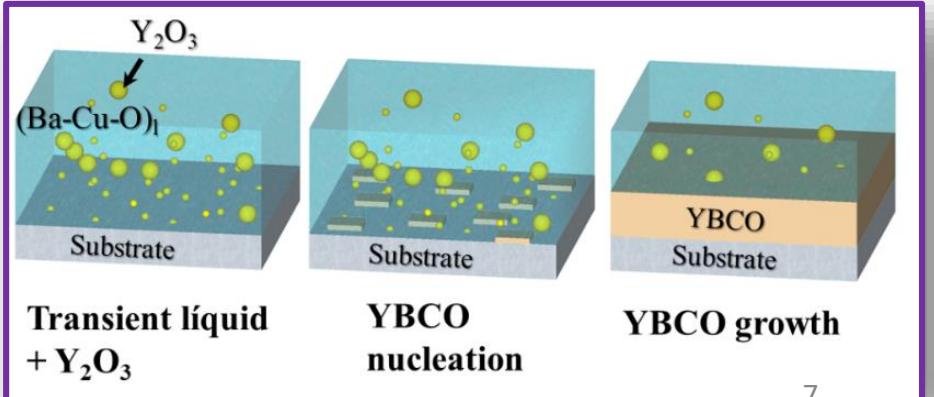
Need of advanced characterization for process understanding and optimization by in-situ growth at light sources:

- X-ray diffraction (phase transformations and orientation)

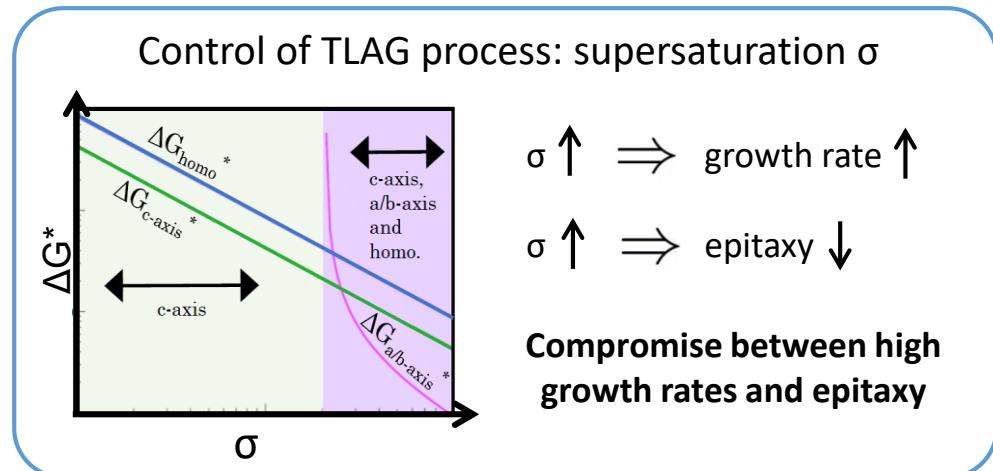
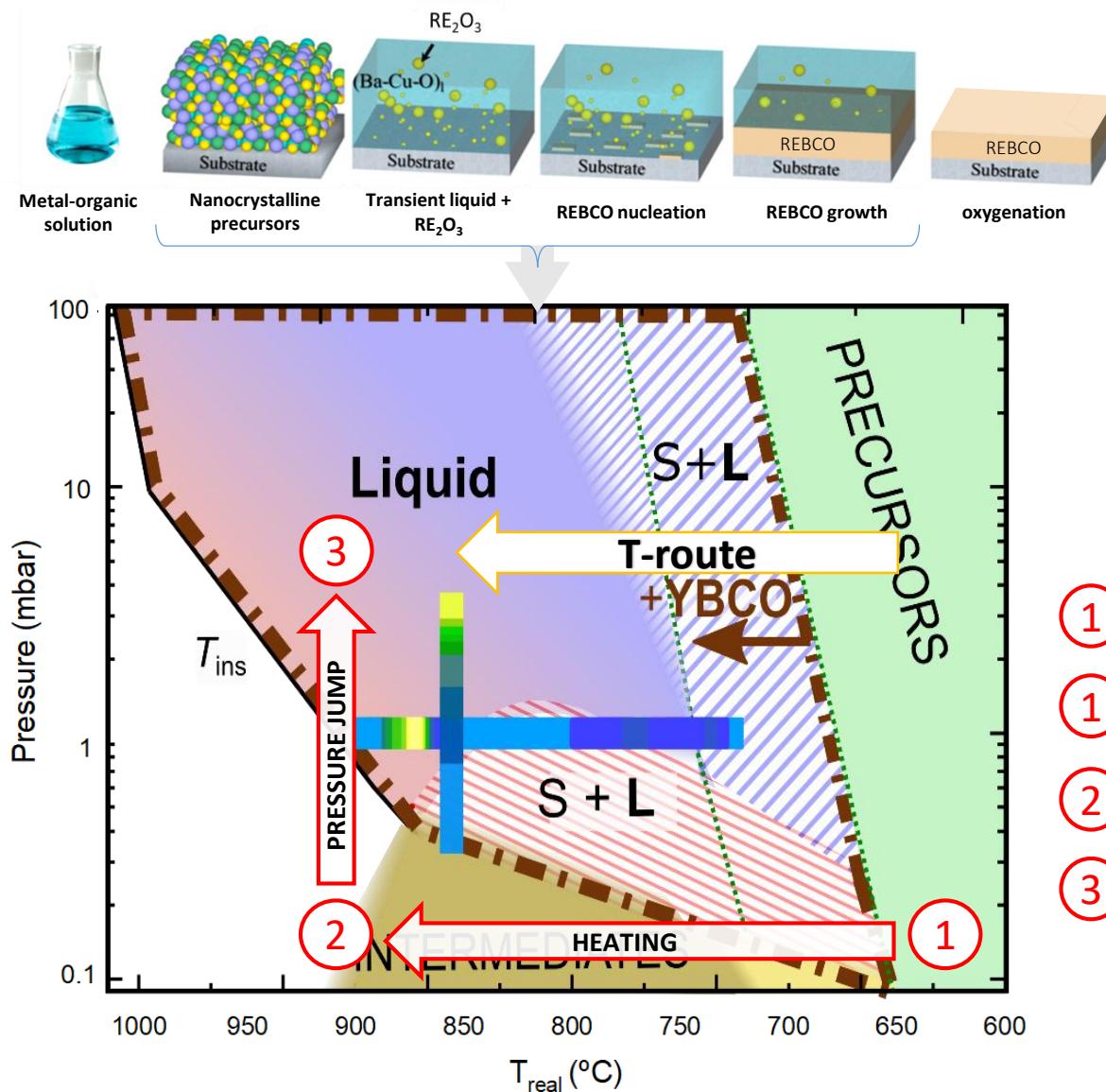
TLAG process
Ultrafast kinetic growth

High temperature crystallization

Experiment conditions:
 P_T , P_{O_2} , Temperature, heating and pressure ramp, gas velocity,...



TLAG growth control and characterization

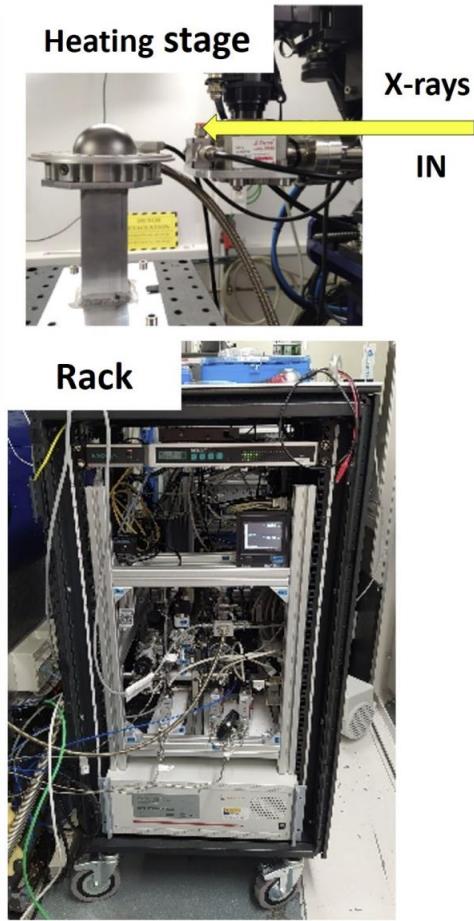
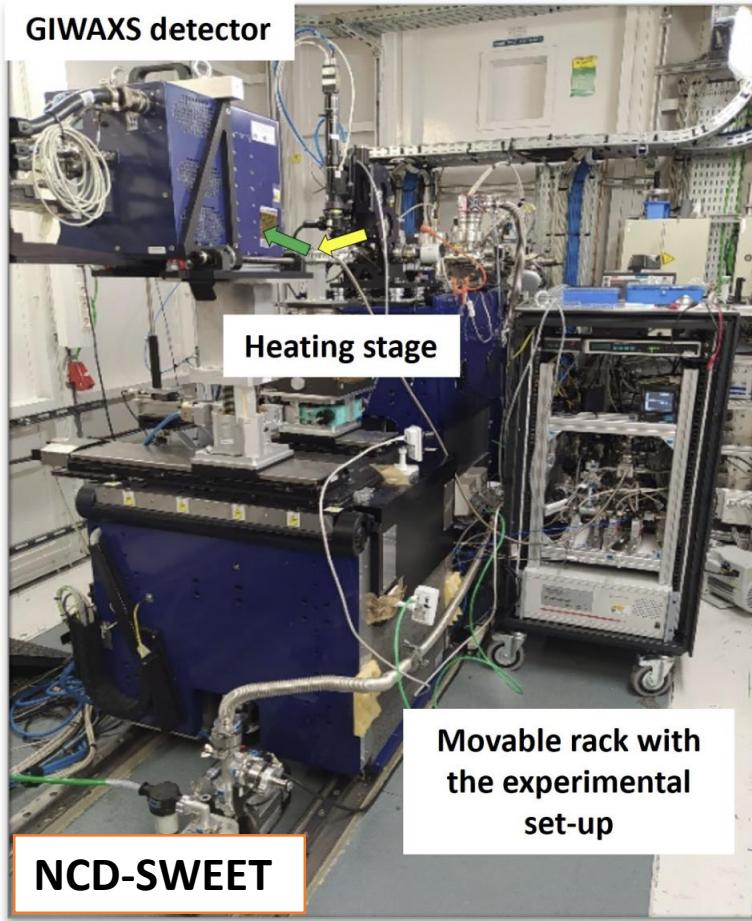
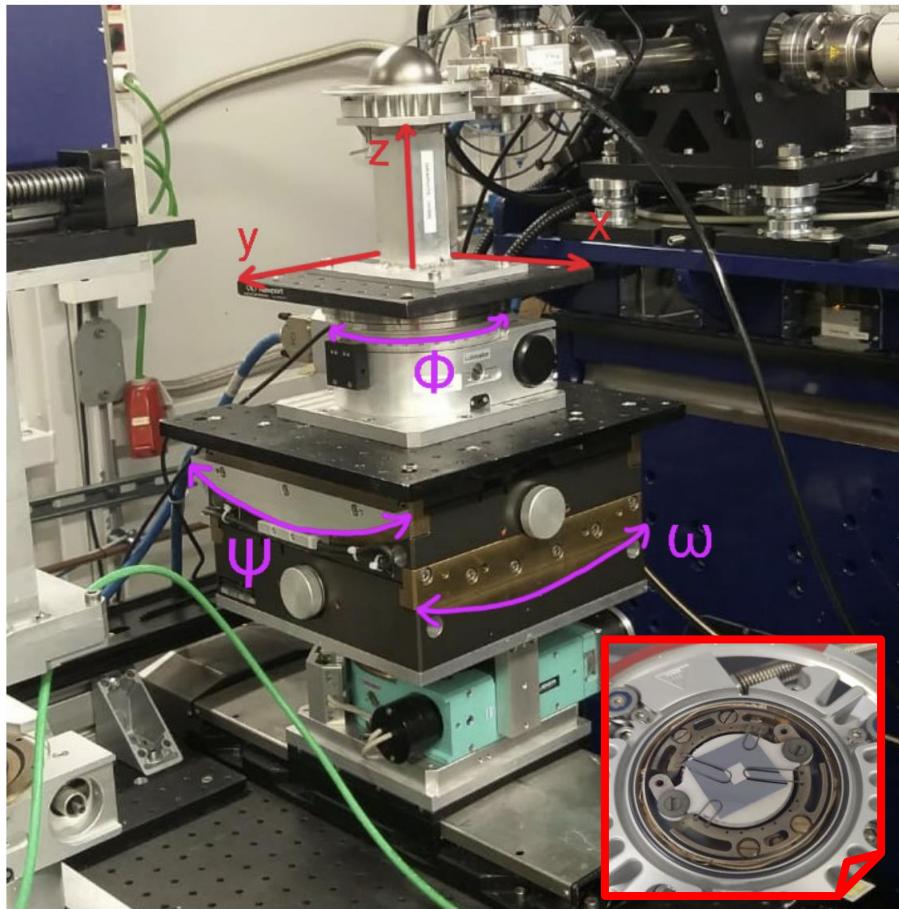


- ① Nanocrystalline precursors: $\text{BaCO}_{3(s)} + \text{CuO}_{(s)} + \text{Y}_2\text{O}_{3(s)}$
- ① HEATING → ② Intermediate reactions
- ② PRESSURE JUMP → ③ Transient liquid formation: $(\text{Ba} - \text{Cu}^{I/II} - \text{O})_{(l)} + \text{Y}_2\text{O}_{3(s)}$
- ③ REBCO growth: $\text{YBa}_2\text{Cu}_3\text{O}_{7-\delta}$



In-situ XRD at ALBA
Synchrotron enables
studying intermediate
phase evolution and
TLAG non-equilibrium
growth mechanism

Enabling *in-situ* XRD characterization of TLAG at



- Rayonix 2D (GI)WAXS CCD detector (1920 x 5760 pixels)
- Pixel size: 44.27 x 44.27 μm
- Tunable Sample \leftrightarrow Detector distance (<300 mm)
- Down to 100 ms per XRD frame

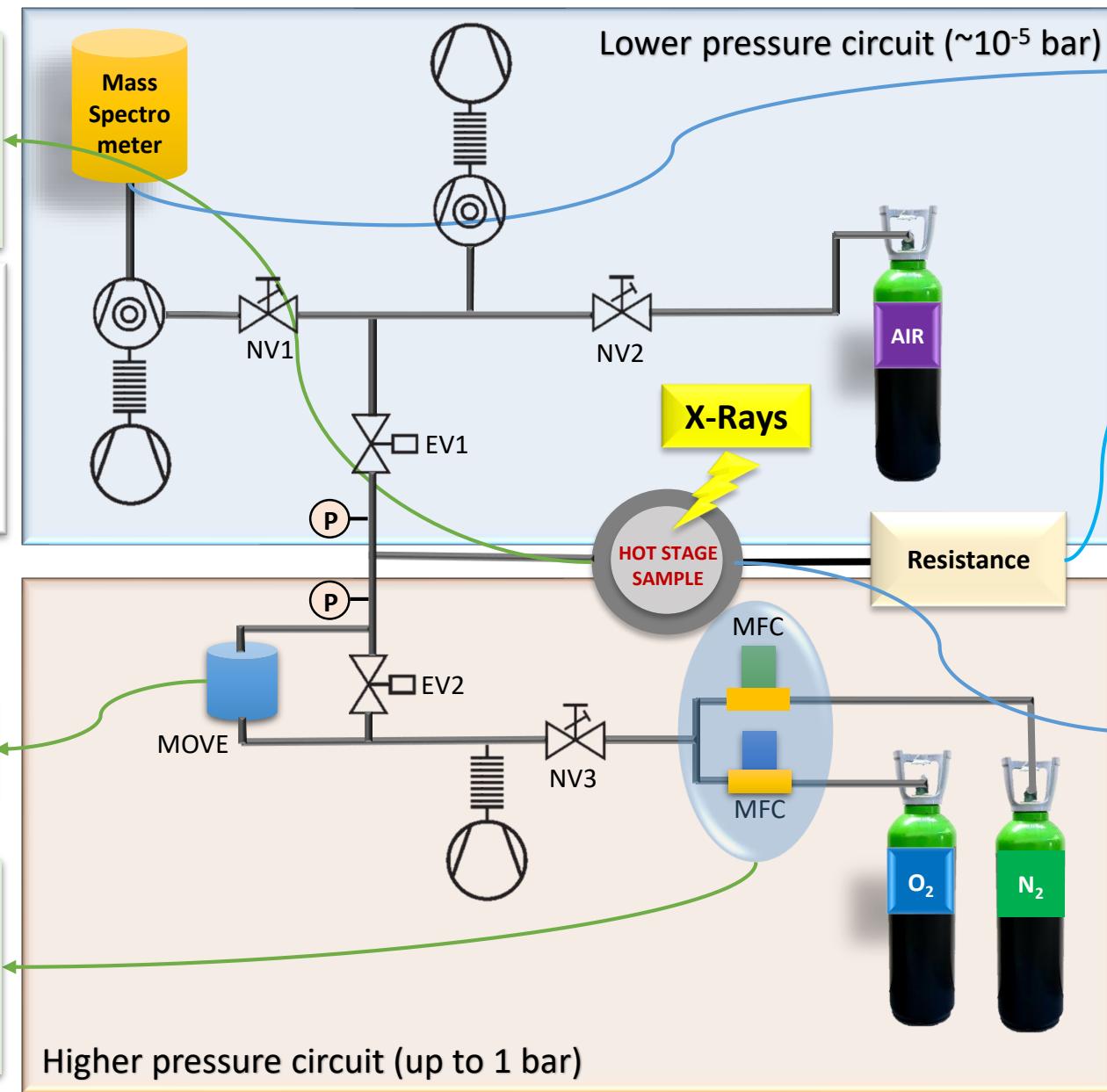
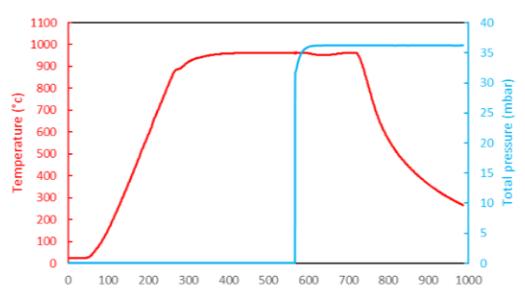
* $t = 400 \text{ nm}$

G of up to
2000 nm/s*

18 keV	YBCO (005)	YBCO (103)	BaCuO ₂	BaCO ₃	Y ₂ O ₃	CuO
2θ positions [°]	16,99	14,50	12,97/12,6 1/13,32	10,6/ 11,9	12,9	15,7/17,08

In-situ TLAG-XRD-R-MS

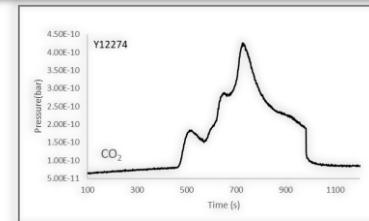
- ✓ Temperature of the reaction (up to 1000° C)
- ✓ Heating rate (up to 300° C/min)
- ✓ T change at the pressure jump (calibration of the PID)



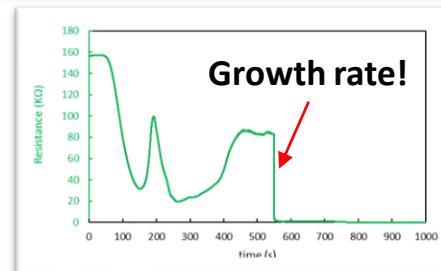
- ✓ Velocity of the pressure jump (0.4 s - minutes)

- ✓ Total pressure (up to 1 bar)
 - ✓ Oxygen partial pressure (1 - 15 mbar)
 - ✓ Flow rate (300 - 1000 ml/min)

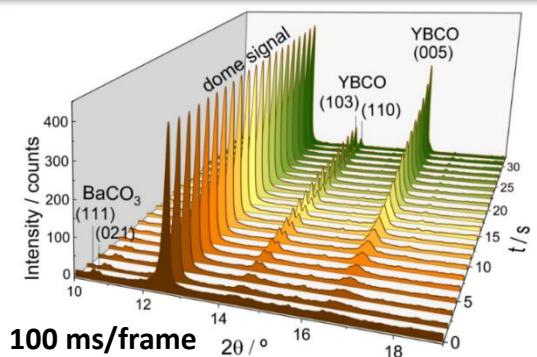
- ✓ Volatile products of reaction: BaCO3 decomposition



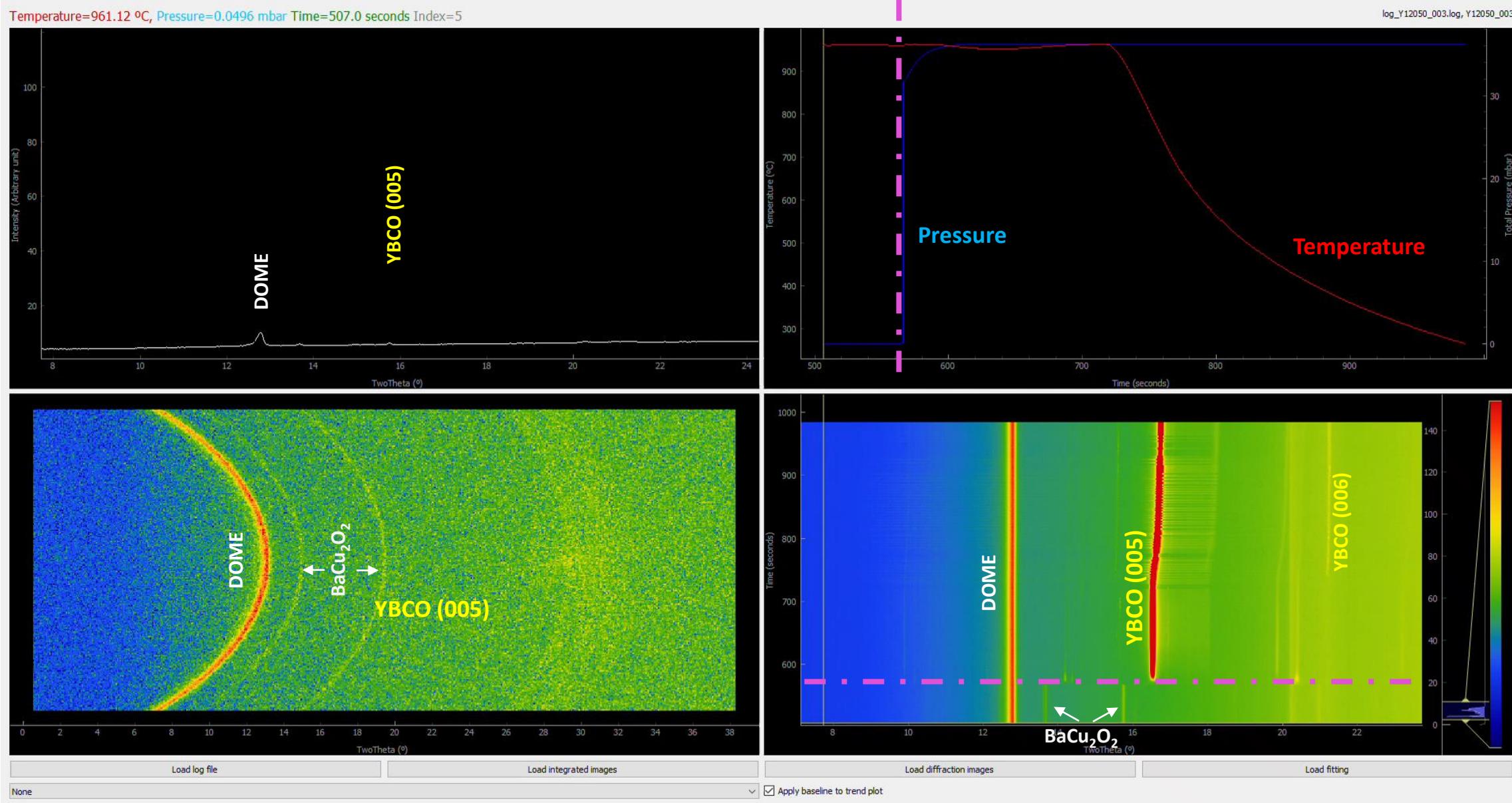
- ✓ Resistance of the film (insulator to metallic transition)



- ✓ X-Ray Diffraction

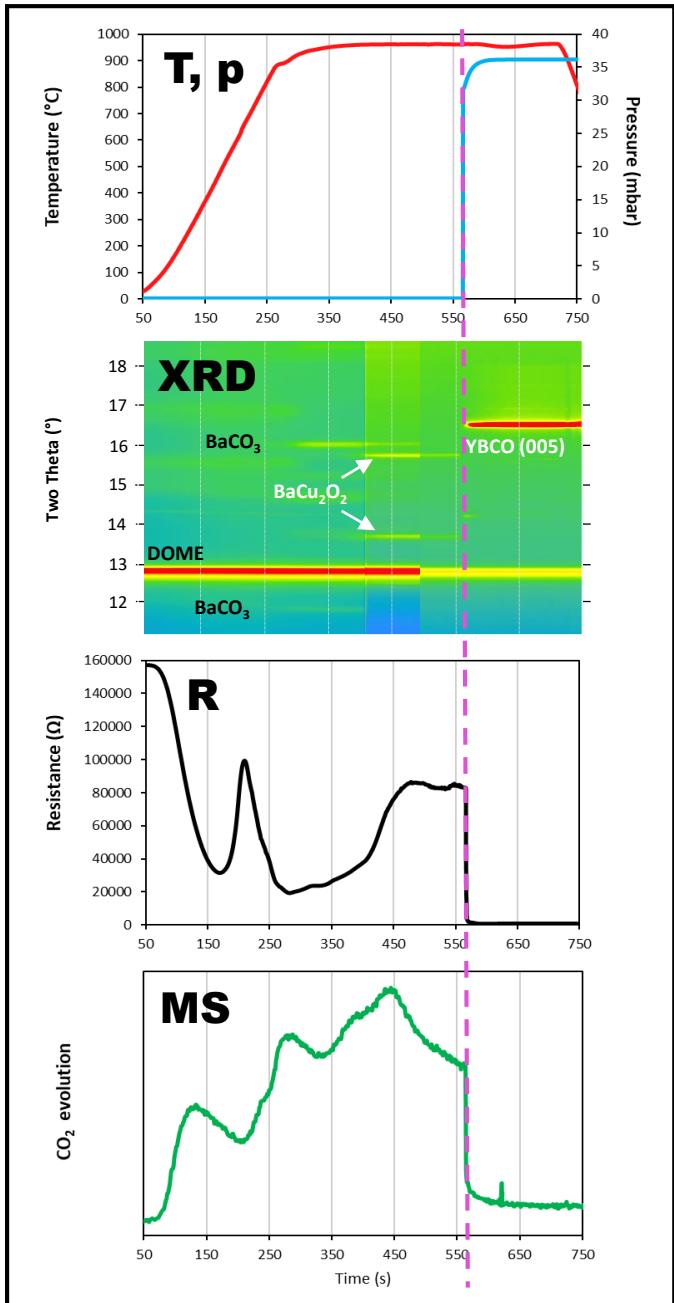


In-situ TLAG-XRD



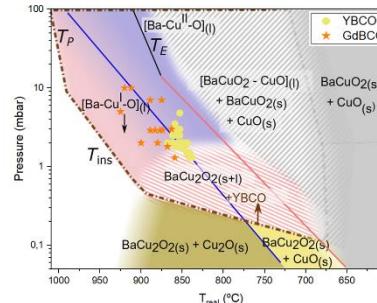
TLAG visualizer developed by Jordi Aguilar
(now part of the ALBA Controls)

In-situ TLAG-XRD-R-MS

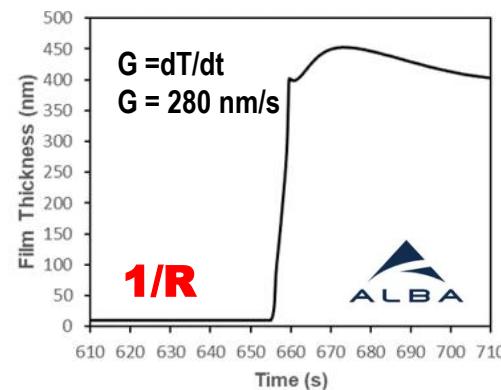
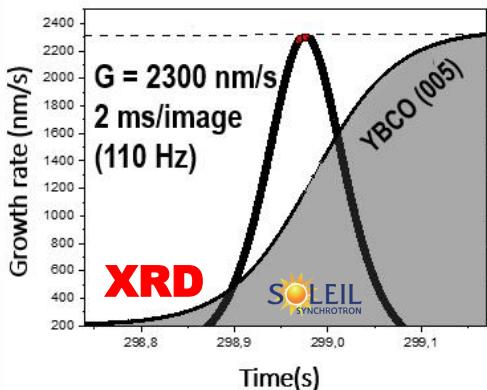


✓ Time-correlated data

For every XRD point: T , p and MS are collected



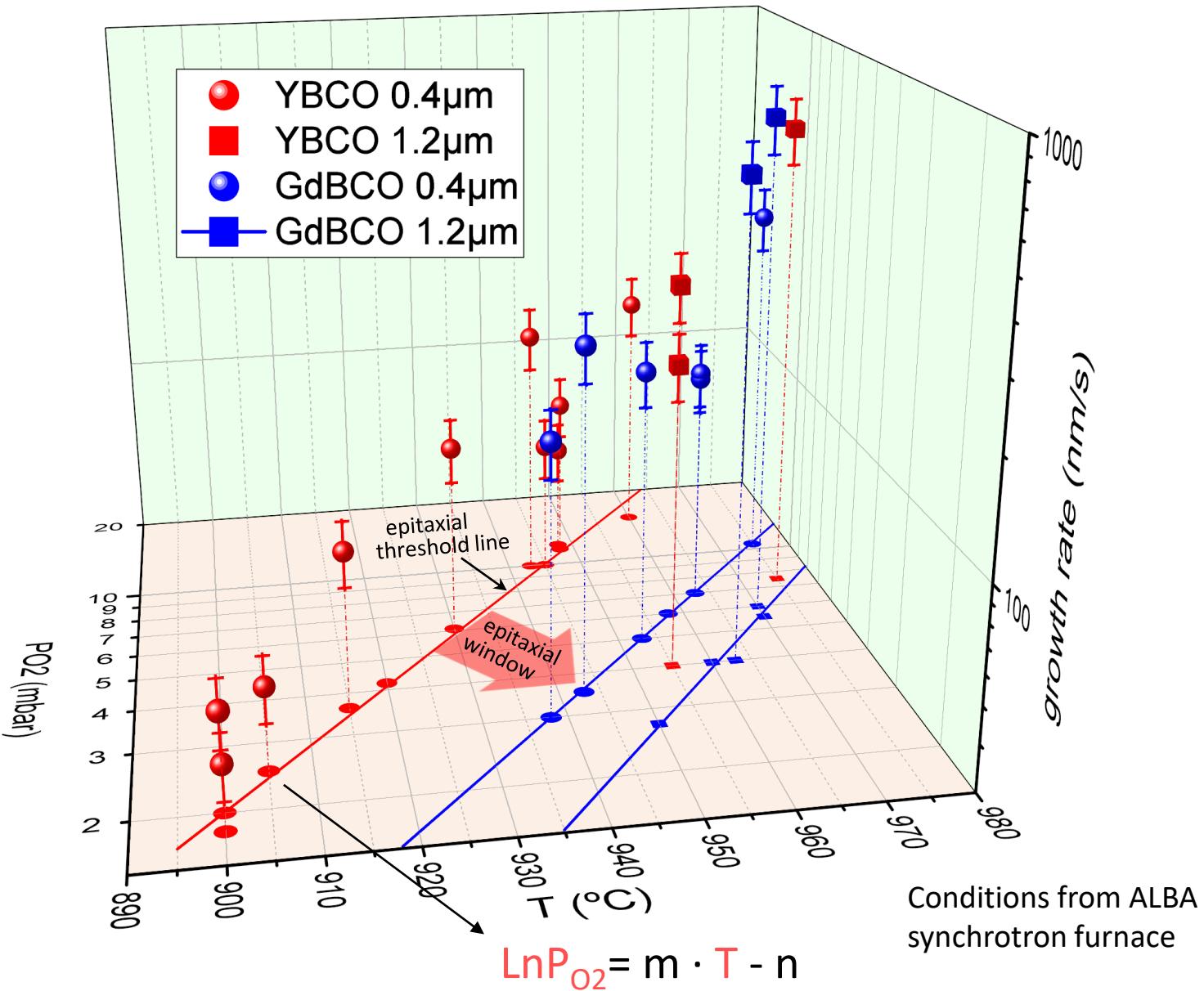
✓ Growth rate calculation: two methods



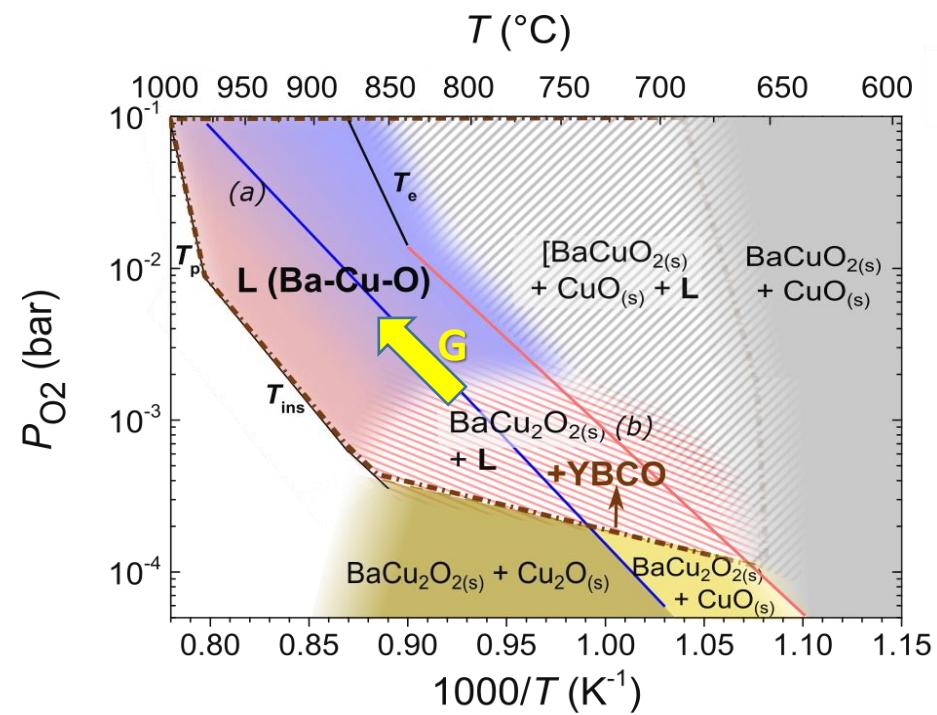
✓ The BaCO_3 decomposition: crucial step



Growth rate dependence on TLAG growth conditions



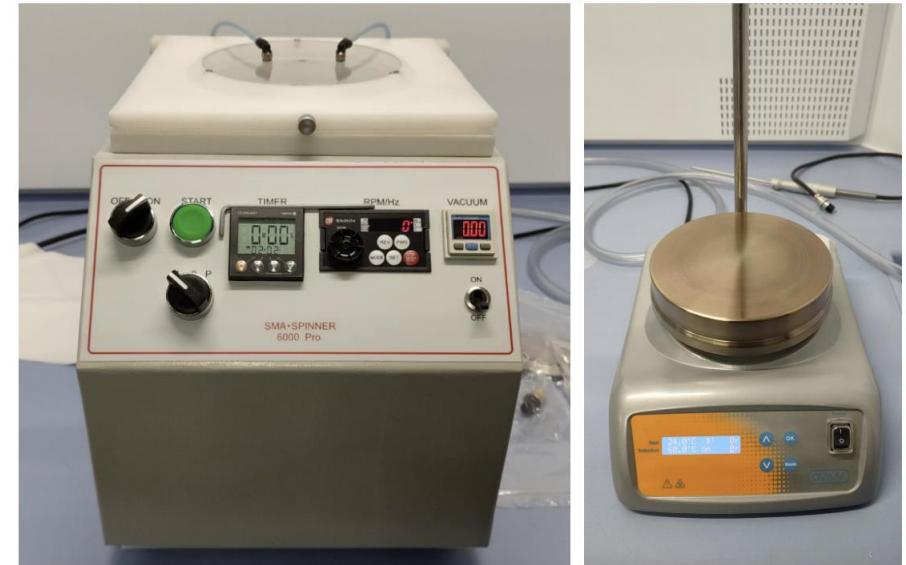
Growth rate, G , \uparrow if P_{O_2} (and T) \uparrow



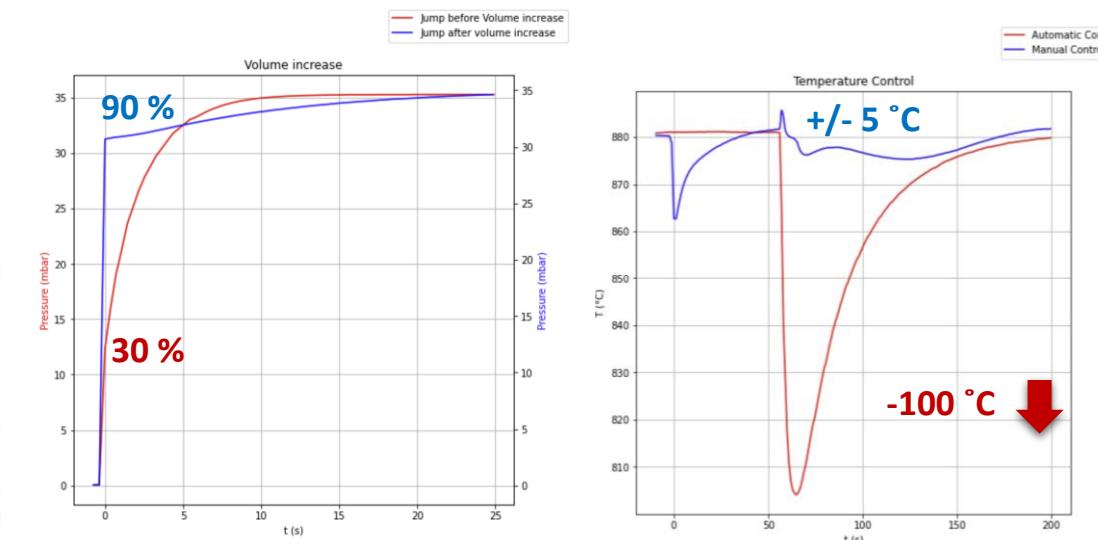
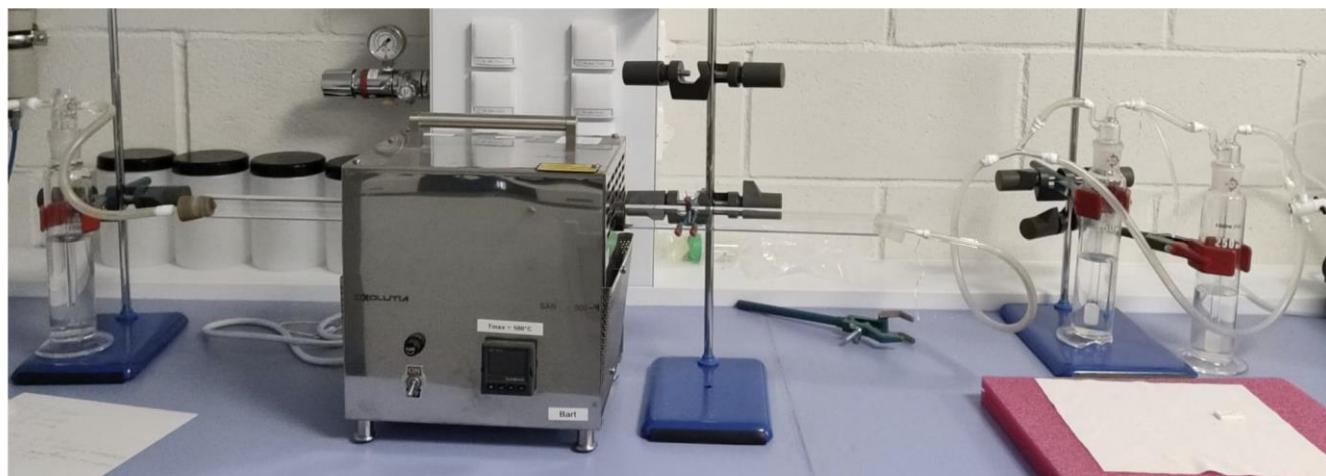
Sample preparation and test laboratory at ALBA (Battery Lab)



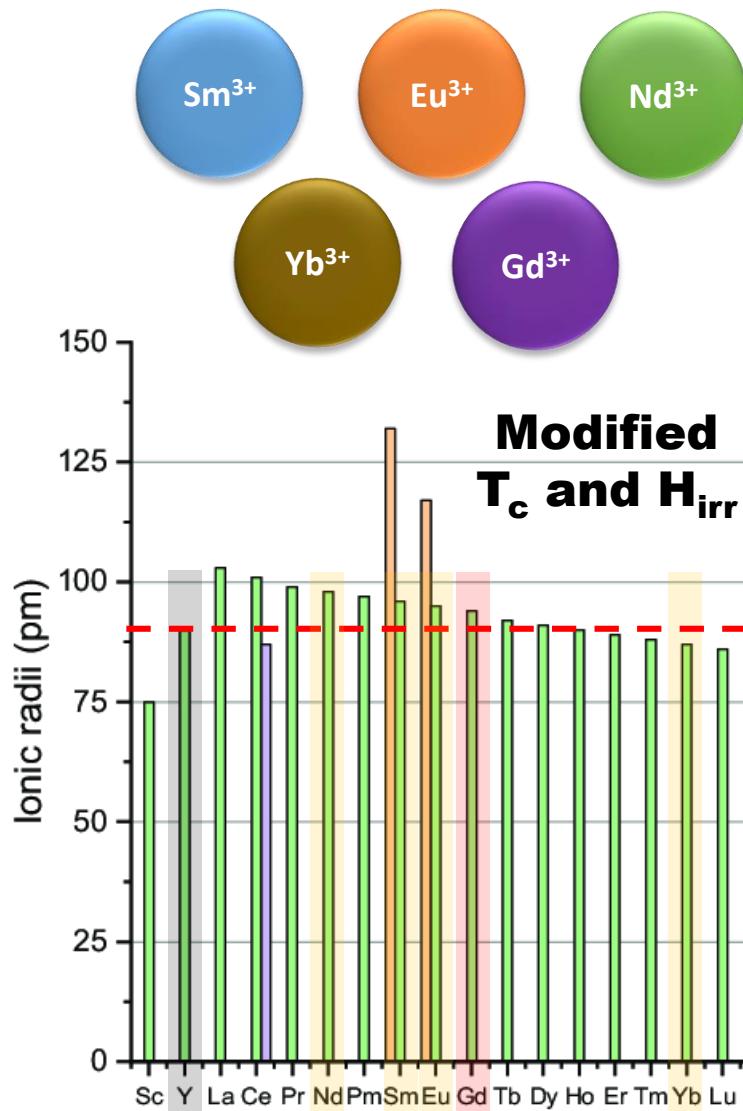
Deposition, pyrolysis and growth



Pre-beamtime calibrations and tests

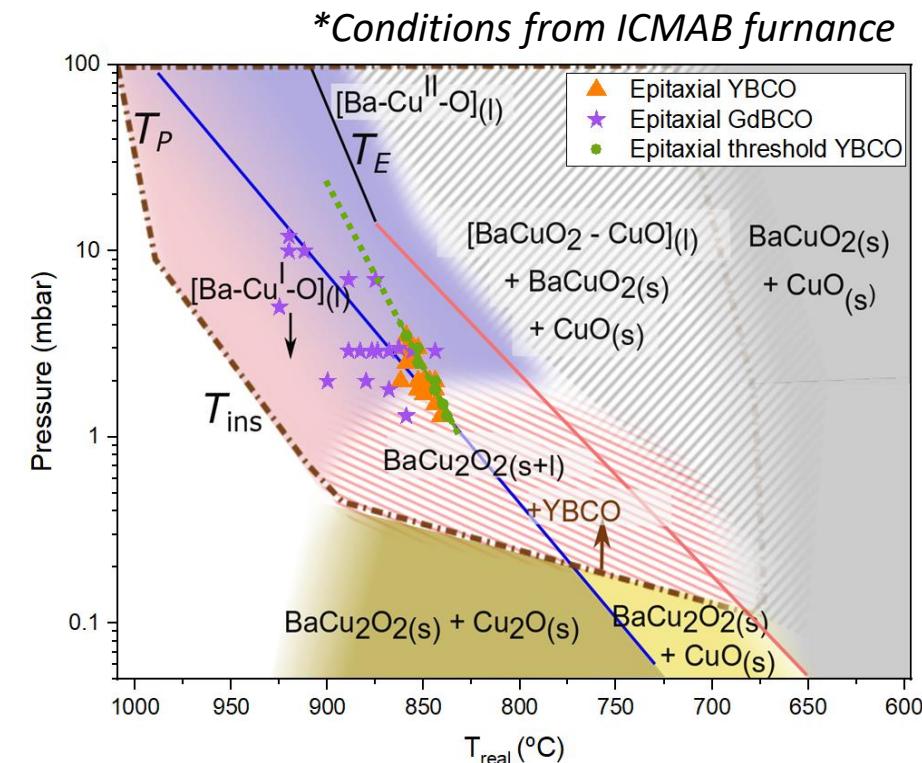


Effect of the Rare Earth on TLAG



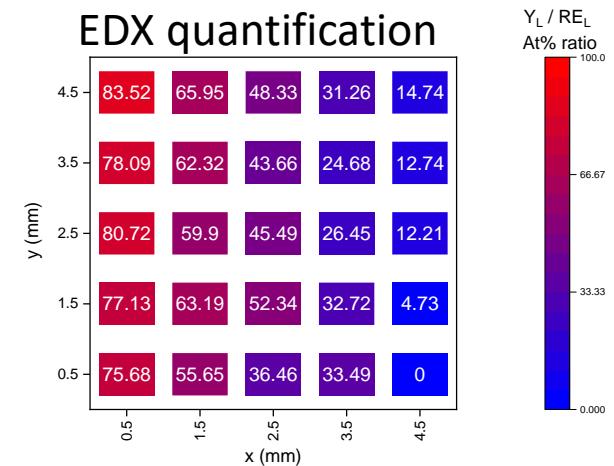
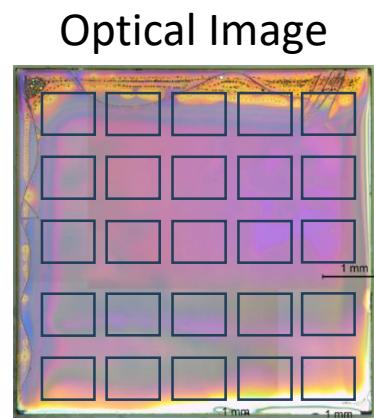
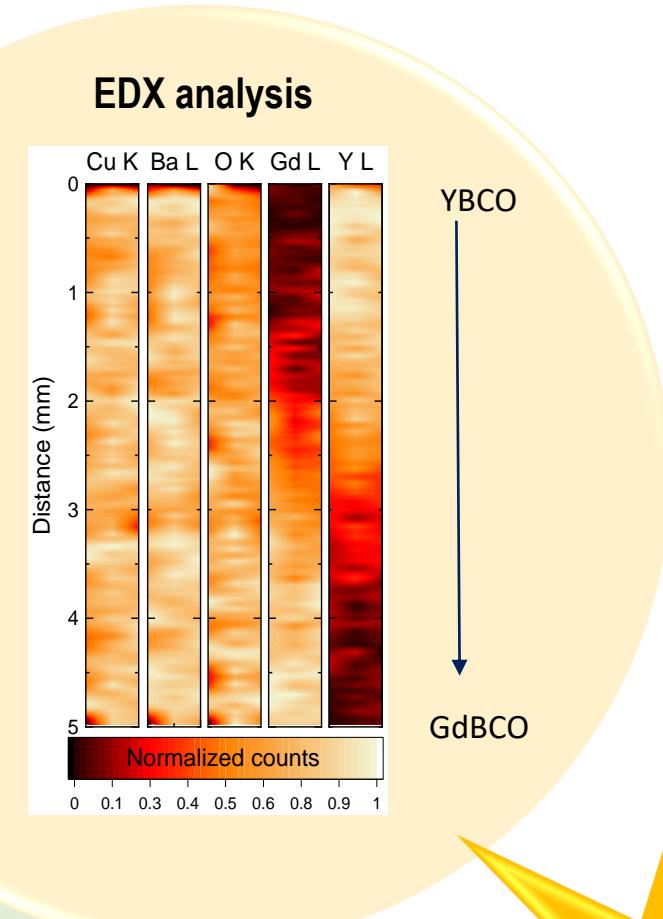
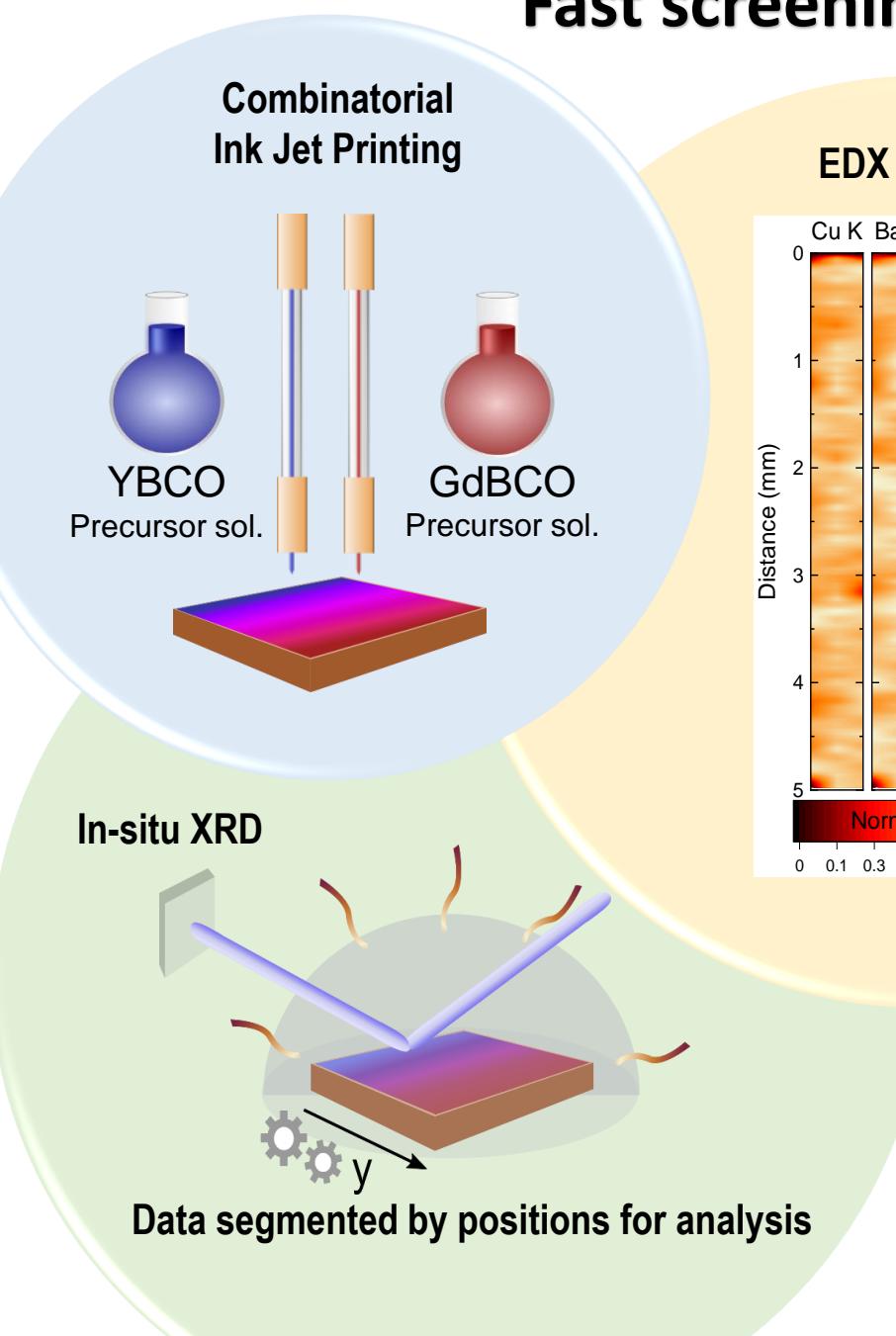
In TLAG the RE modifies:

- Epitaxial windows
- Supersaturation value
- Solubility in the liquid
- Nucleation density
- Growth rate

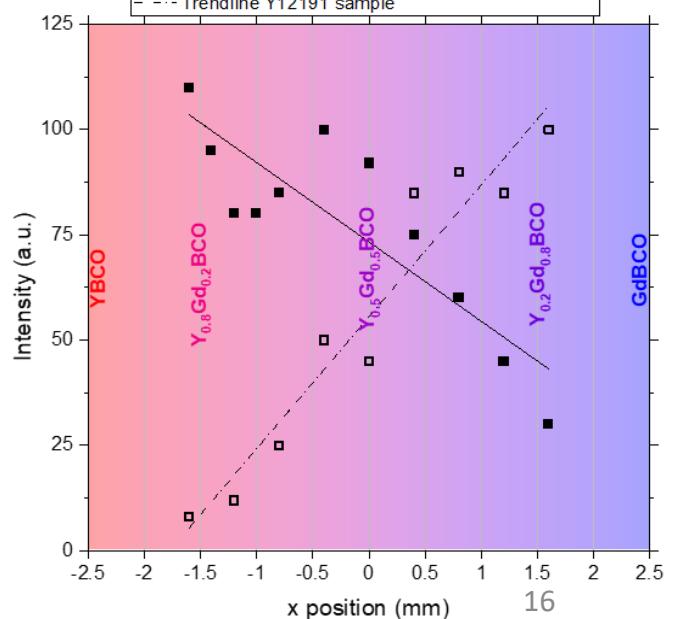


Wide range of conditions of p_{O_2} and temperature has been demonstrated for the c-axis YBCO and GdBCO TLAG growth

Fast screening approach with mixed REBCO

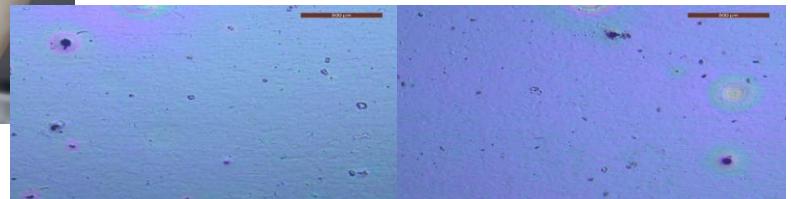
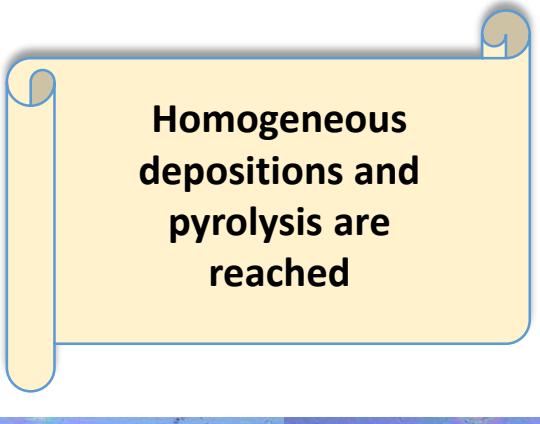
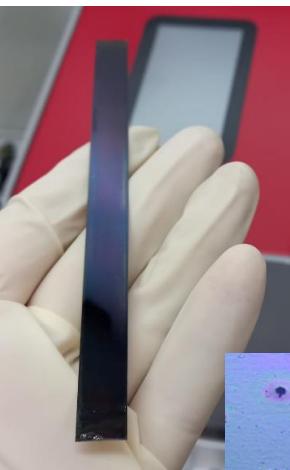
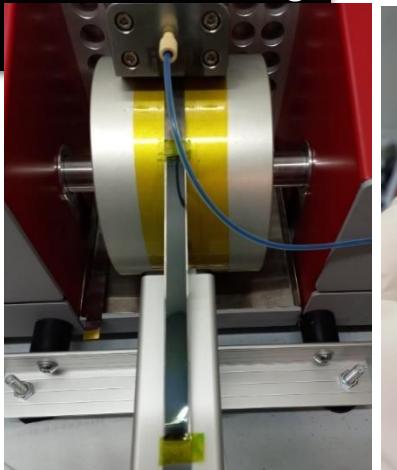


Fast screening across varying compositions



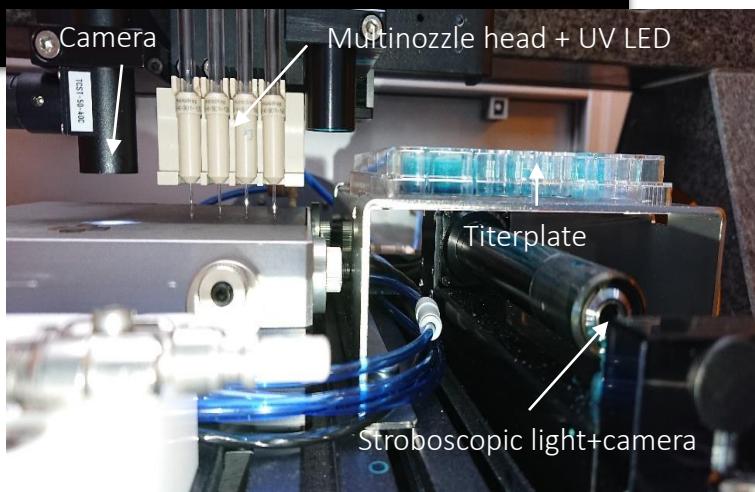
Towards industrialization of TLAG

Slot-die coating

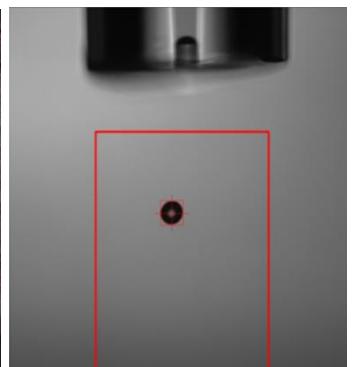


15 cm, pyrolyzed film (6 layers, ~3 μ m)

Ink Jet Printing deposition



Piece of 6.5 cm pyrolyzed tape with 6 layers

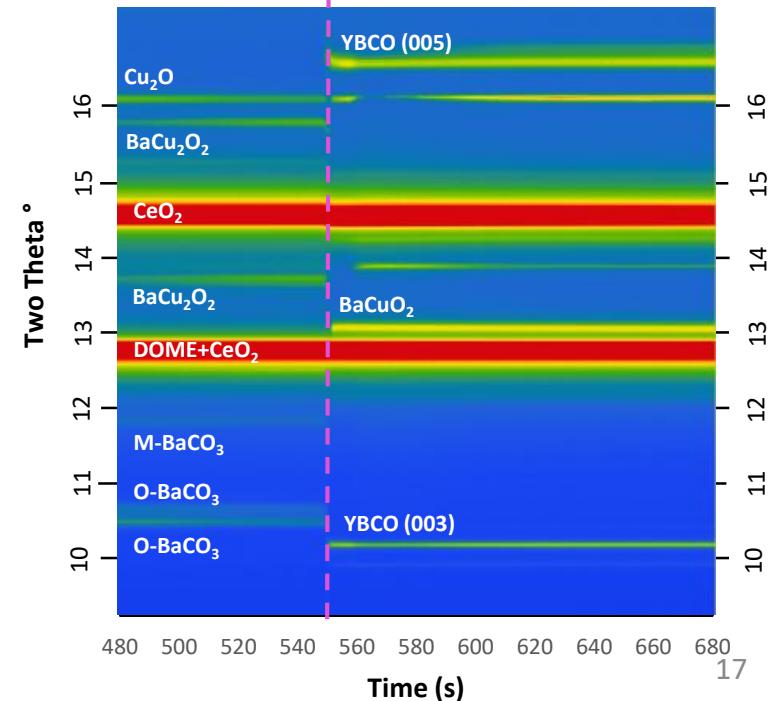
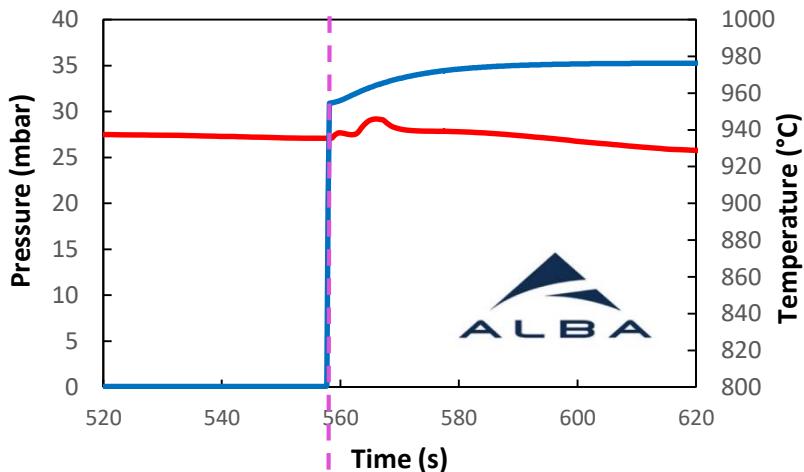


Drop Diameter: 63 μ m
Drop Volume: 131 pl



1.7 μ m
pyrolyzed film
(1 layer)

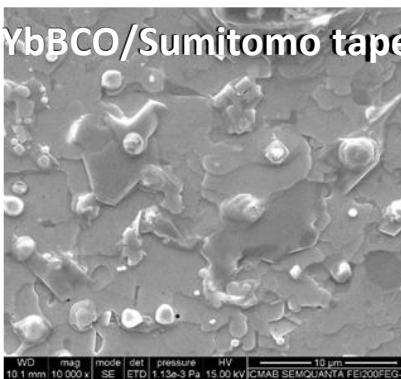
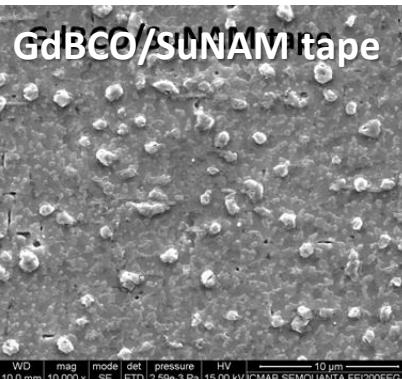
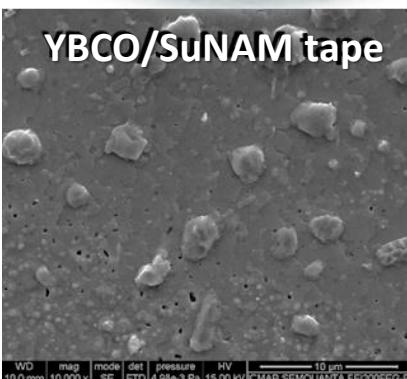
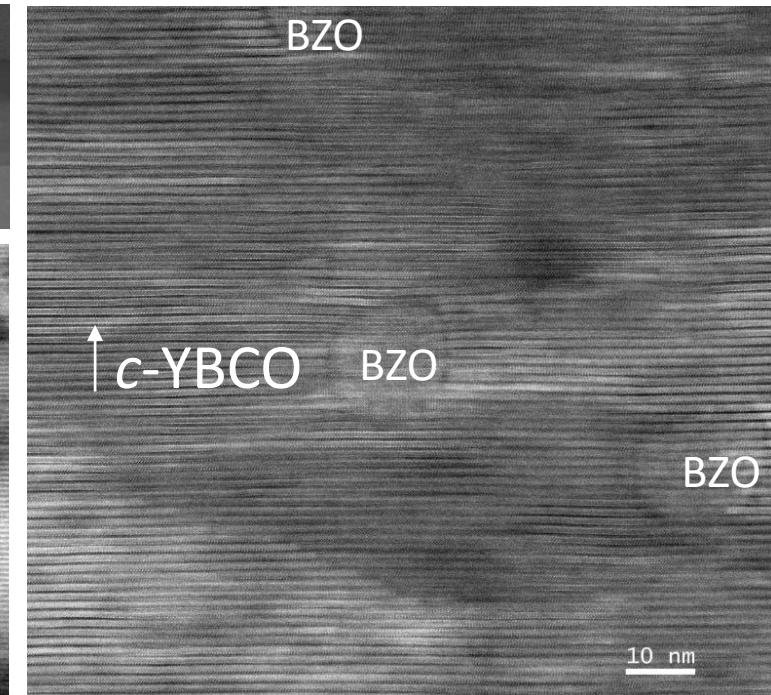
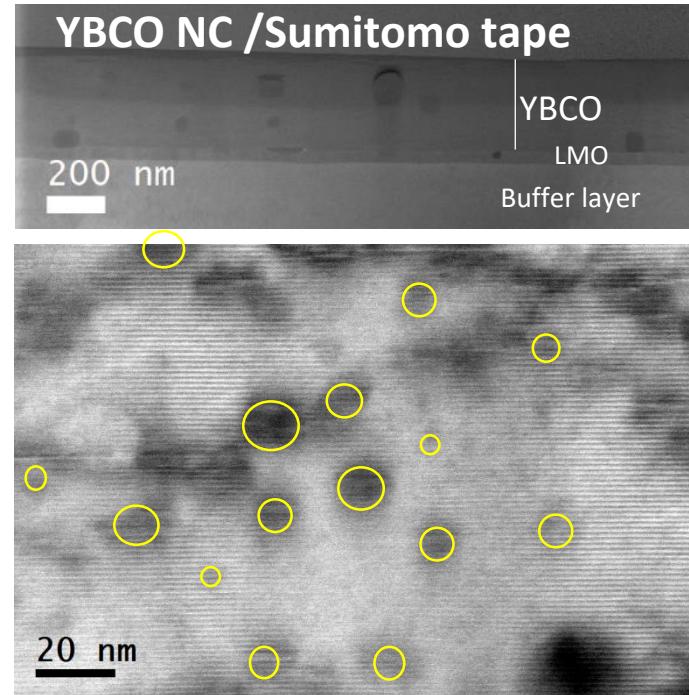
In-situ TLAG-XRD



TLAG Coated conductors



Slot die
now with 40 mm-width
printhead capabilities

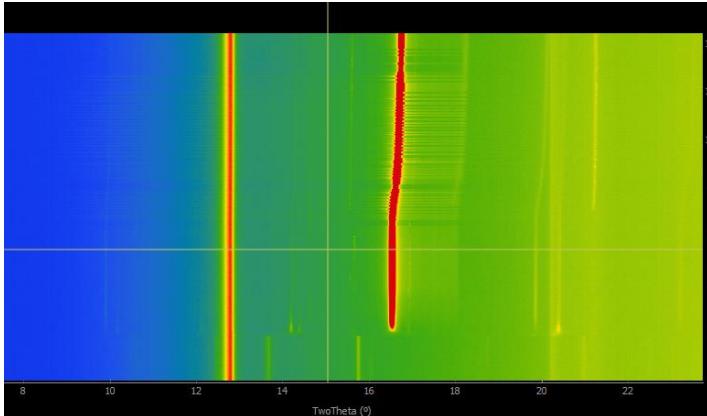


Microstructure is reproduced in 250-750 nm CC
High superconducting properties: $J_c(77K) = 1.7\text{-}2 \text{ MA/cm}^2$

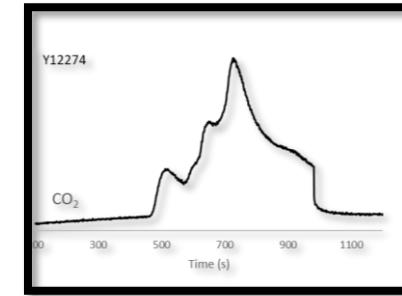
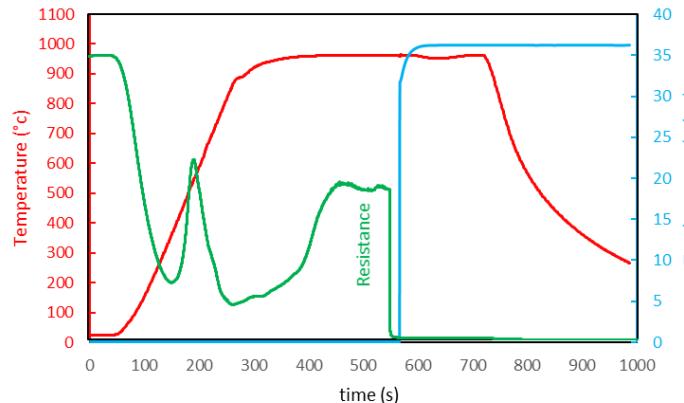
FUTURE

Correlative characterization

In-situ TLAG-X-RAY DIFFRACTION



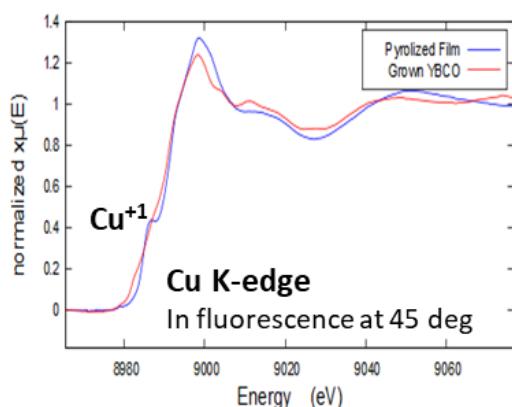
NCD-SWEET beamline



In-situ TLAG-X-RAY ABSORPTION

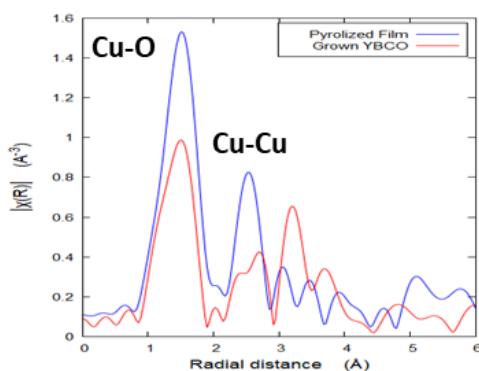
XANES

local electronic structure



EXAFS

first-order atomic pair correlation



CLAESS
beamline

- ✓ Amorphous Transient Liquid
- Cu valence state

- ✓ Different liquid composition
- effect on the Cu valence

Summary

***In-situ* X-Ray Diffraction:**

- Essential to reveal the mechanisms of the TLAG growth of REBCO films
- Build non-equilibrium kinetic phase diagrams
- Correlation between precursors, intermediates, and final films with T, p, mass spectrometry and resistance

TLAG :

- non-equilibrium process kinetically controlled by supersaturation of the rare earth in the liquid
- ultrafast growth rates
- high performance films
- relatively low cost to performance ratio method
- may revolutionize the industrial applications of REBCO

Acknowledgements



Eduardo Solano
Marc Malfois

} NCD-SWEET

Laura Simonelli - CLAESS

ALBA Safety Department



Cristian Mocuta – DiffAbs

 suman



Carla Torres, Emma Ghiara, Ona Mola – current PhDs

Jordi Aguilar – currently at ALBA Controls Department

Daniel Sanchez, Jordi Farjas - University of Girona

Victor Fuentes – Technician at the Battery Lab, ALBA